

1. General description

WeEnPACK-B2 module with WeEn 1200V Gen2 SiC MOSFET and Solder pin type. Integrated with NTC temperature sensor.



2. Features and benefits

- Half bridge topology
- Solder pin configuration
- Low $R_{DS(on)}-T_j$ coefficient
- Low Switching Losses
- Low Q_g and C_{rss}
- Mimimized circuit impedance
- Improved chip synchronization performance

3. Applications

- Power inverters
- AC-DC converters
- DC-DC converters
- Active power factor correctors
- Motor drives


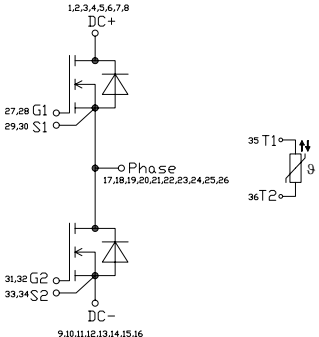
4. Quick reference data

Table 1. Quick reference data

| Symbol | Parameter | Conditions | Notes | Values | | | Unit |
|--------------------------------|----------------------------------|---|-------|--------|------------|-----|------------------|
| Absolute maximum rating | | | | | | | |
| V_{DS} | drain-source voltage | $T_j = 25\text{ }^\circ\text{C}$ | | | 1200 | | V |
| I_D | drain current | $V_{GS} = 18\text{ V}; T_h = 25\text{ }^\circ\text{C}$ | | | 157 | | A |
| P_{tot} | total power dissipation | $T_h = 25\text{ }^\circ\text{C}$ | | | 272 | | W |
| $T_{j,op}$ | operating junction temperature | | | | -40 to 150 | | $^\circ\text{C}$ |
| Symbol | Parameter | Conditions | Notes | Min | Typ | Max | Unit |
| Static characteristics | | | | | | | |
| $R_{DS(on)}$ | drain-source on-state resistance | $V_{GS} = 15\text{ V}; I_D = 150\text{ A}; T_j = 25\text{ }^\circ\text{C}$ | | - | 8.0 | - | m Ω |
| | | $V_{GS} = 18\text{ V}; I_D = 150\text{ A}; T_j = 25\text{ }^\circ\text{C}$ | | - | 6.7 | 13 | m Ω |
| Dynamic characteristics | | | | | | | |
| $Q_{G(tot)}$ | total gate charge | $I_D = 150\text{ A}; V_{DS} = 800\text{ V}; V_{GS} = 0\text{ V}/18\text{ V}; T_j = 25\text{ }^\circ\text{C}$ | | - | 536 | - | nC |
| Q_{GD} | gate-drain charge | | | - | 102 | - | nC |
| Source-drain diode | | | | | | | |
| Q_r | recovered charge | $I_{SD} = 150\text{ A}; V_{GS} = -4\text{ V}/18\text{ V}; V_R = 600\text{ V}; di/dt = 2700\text{ A}/\mu\text{s};$ | | - | 928 | - | nC |

5. Pinning information

Table 2. Pinning information

| Simplified outline | Circuit diagram |
|--|--|
|  <p>* Please refer to the package outline description for actual pin order.</p> |  |

6. Ordering information

Table 3. Ordering information

| Type number | Package Name | Orderable part number | Packing method | Small packing quantity | Package version | Package issue date |
|---------------|--------------|-----------------------|----------------|------------------------|------------------|--------------------|
| WMSC008H12B2S | WeEnPACK-B2 | WMSC008H12B2S6T | Tray | 14 | WeEnPACK-B2PHB-A | 31-Jan-2024 |

7. Marking

Table 4. Marking codes

| Type number | Marking codes |
|---------------|---------------|
| WMSC008H12B2S | WMSC008H12B2S |

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | Notes | Values | Unit |
|-------------------|--|--|-------|------------|------|
| T_{stg} | storage temperature | | | -40 to 125 | °C |
| $T_{j,op}$ | operating junction temperature | | | -40 to 150 | °C |
| $T_{j,max}$ | maximum junction temperature | Intermittent condition with shortened lifetime | | -40 to 175 | °C |
| V_{ISOL} | RMS isolation voltage | $T_j = 25\text{ °C}$; all terminals shorted; $f = 50\text{ Hz}$; $t = 1\text{ s}$ | | 3500 | V |
| MOSFET | | | | | |
| V_{DS} | drain-source voltage | $T_j = 25\text{ °C}$ | | 1200 | V |
| $V_{GS,max}$ | gate-source voltage | Absolute maximum values | | -12 to 24 | V |
| $V_{GS,op}$ | gate-source voltage | Recommended operational values | | -4 to 18 | V |
| P_{tot} | total power dissipation | $T_h = 25\text{ °C}$ | | 272 | W |
| I_D | drain current | $V_{GS} = 18\text{ V}$; $T_h = 25\text{ °C}$ | | 157 | A |
| | | $V_{GS} = 18\text{ V}$; $T_h = 100\text{ °C}$ | | 99 | A |
| I_{DM} | peak drain current | pulsed; $t_p \leq 10\text{ us}$; $T_h = 25\text{ °C}$ | | 350 | A |
| E_{as} | single pulse drain-to-source avalanche | $I_{AS} = 24\text{ A}$; $L = 1\text{ mH}$; $V_{DD} = 100\text{ V}$; $T_{j(init)} = 25\text{ °C}$; each die | | 288 | mJ |
| Body Diode | | | | | |
| I_{SD} | DC body diode forward current | $T_h = 25\text{ °C}$; $V_{GS} = -4\text{ V}$ | | 65 | A |
| $I_{SD,pulse}$ | Pulse body diode current | verified by design, t_p limited by $T_{j,max}$ | | 350 | A |

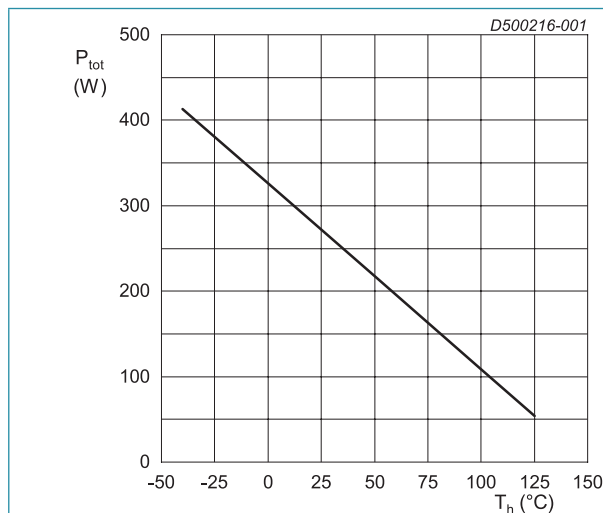


Fig. 1. Power dissipation as a function of heatsink temperature; maximum values

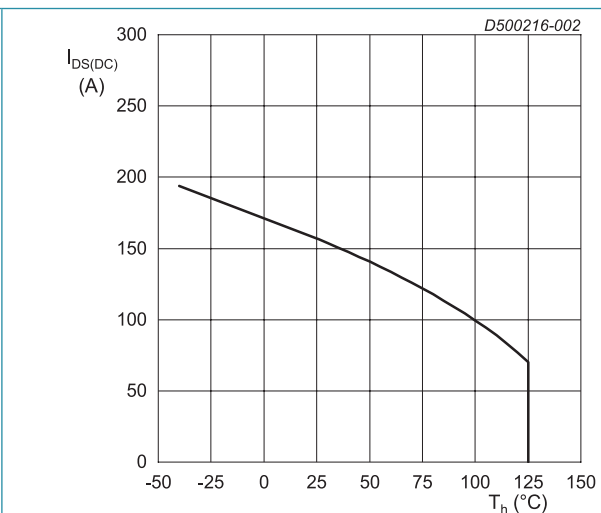


Fig. 2. Continuous Drain Current as a function of heatsink temperature

9. Thermal & Mechanical characteristics

Table 6. Thermal & Mechanical characteristics

| Symbol | Parameter | Conditions | Notes | Min | Typ | Max | Unit |
|---------------------------|--|---|-------|--------------------------------|------|-----|------|
| $R_{th(j-c)}$ | thermal resistance from junction to case | per MOSFET | | - | 0.16 | - | K/W |
| $R_{th(j-h)}$ | thermal resistance from junction to heatsink | per MOSFET, $\lambda_{grease} = 3 \text{ W/(m}\cdot\text{K)}$, $thick_{grease} = 50 \text{ }\mu\text{m}$ | | - | 0.46 | - | K/W |
| Internal Isolation | | basic insulation (class 1, IEC 61140) | | Al ₂ O ₃ | | | |
| d_{Creep} | Creepage distance | terminal to heatsink | | - | 11.5 | - | mm |
| | | terminal to terminal | | - | 6.3 | - | mm |
| d_{Clear} | Clearance | terminal to heatsink | | - | 10 | - | mm |
| | | terminal to terminal | | - | 5 | - | mm |
| CTI | Comperative tracking index | | | >200 | | | |
| F | Mounting force per clamp | | | 40 | - | 80 | N |
| G | Approximate Weight | | | - | 36 | - | g |

Note: Module is ESD sensitive. Handling precautions are recommended.

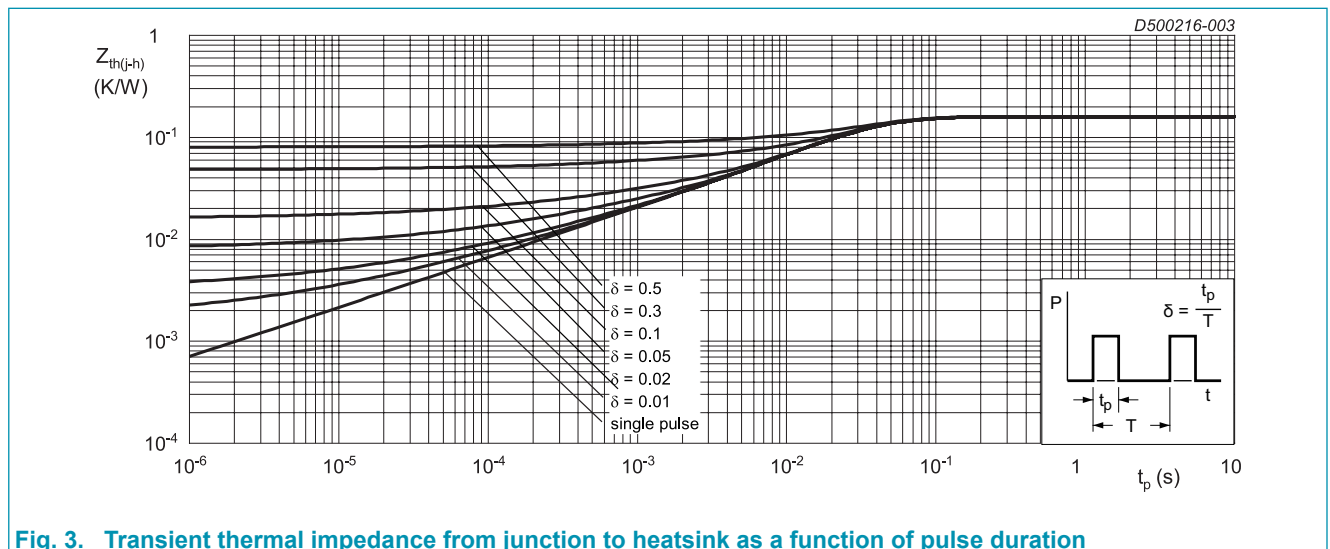


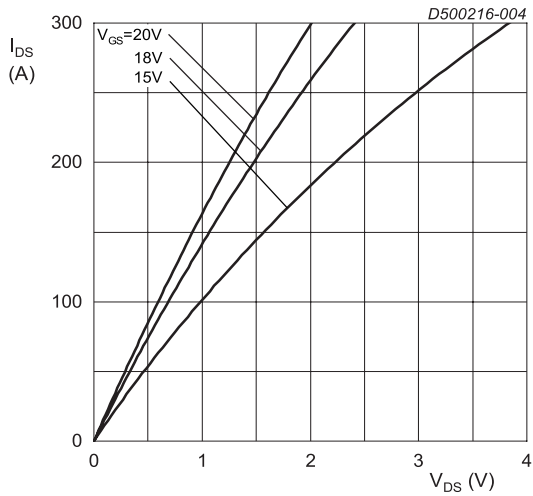
Fig. 3. Transient thermal impedance from junction to heatsink as a function of pulse duration

10. Characteristics

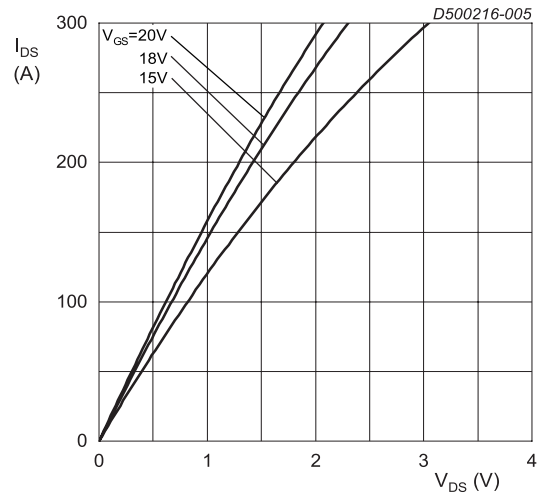
Table 7. Characteristics

| MOSFET | | | | | | | | |
|--------------------------------|---------------------------------------|--|--|------|------|-----|------------|----|
| Symbol | Parameter | Conditions | Notes | Min | Typ | Max | Unit | |
| Static characteristics | | | | | | | | |
| $V_{(BR)DSS}$ | drain-source breakdown voltage | $I_D = 400 \mu A$; $V_{GS} = 0 V$; $T_j = 25 \text{ }^\circ C$ | | 1200 | - | - | V | |
| $V_{GS(th)}$ | gate-source threshold voltage | $I_D = 48 \text{ mA}$; $V_{DS} = 10 V$; $T_j = 25 \text{ }^\circ C$ | | 1.9 | 2.5 | 3.5 | V | |
| | | $I_D = 48 \text{ mA}$; $V_{DS} = 10 V$; $T_j = 175 \text{ }^\circ C$ | | - | 1.9 | - | V | |
| I_{DSS} | drain leakage current | $V_{DS} = 1200 V$; $V_{GS} = 0 V$; $T_j = 25 \text{ }^\circ C$ | | - | 1 | 400 | μA | |
| I_{GSS} | gate leakage current (absolute value) | $V_{GS} = 24 V$; $V_{DS} = 0 V$; $T_j = 25 \text{ }^\circ C$ | | - | 40 | 400 | nA | |
| | | $V_{GS} = -12 V$; $V_{DS} = 0 V$; $T_j = 25 \text{ }^\circ C$ | | - | 40 | 400 | nA | |
| $R_{DS(on)}$ | drain-source on-state resistance | $V_{GS} = 15 V$; $I_D = 150 A$; $T_j = 25 \text{ }^\circ C$ | | - | 8.0 | - | m Ω | |
| | | $V_{GS} = 18 V$; $I_D = 150 A$; $T_j = 25 \text{ }^\circ C$ | | - | 6.7 | 13 | m Ω | |
| | | $V_{GS} = 18 V$; $I_D = 150 A$; $T_j = 125 \text{ }^\circ C$ | | - | 10 | - | m Ω | |
| | | $V_{GS} = 18 V$; $I_D = 150 A$; $T_j = 150 \text{ }^\circ C$ | | - | 11 | - | m Ω | |
| | | $V_{GS} = 18 V$; $I_D = 150 A$; $T_j = 175 \text{ }^\circ C$ | | - | 11.6 | - | m Ω | |
| R_G | gate resistance | $f = 1 \text{ MHz}$; $T_j = 25 \text{ }^\circ C$; each die with 4.7 Ω $R_{G,ext}$ in series | | - | 1.27 | - | Ω | |
| g_{fs} | transconductance | $V_{DS} = 20 V$; $I_D = 150 A$; $T_j = 25 \text{ }^\circ C$ | | - | 55 | - | S | |
| Dynamic characteristics | | | | | | | | |
| $Q_{G(tot)}$ | total gate charge | $I_D = 150 A$; $V_{DS} = 800 V$; $V_{GS} = 0 V/18 V$; $T_j = 25 \text{ }^\circ C$ | | - | 536 | - | nC | |
| Q_{GS} | gate-source charge | | | - | 172 | - | nC | |
| Q_{GD} | gate-drain charge | | | - | 102 | - | nC | |
| C_{iss} | input capacitance | $V_{DS} = 1000 V$; $V_{GS} = 0 V$; $f = 1 \text{ MHz}$; $T_j = 25 \text{ }^\circ C$ | | - | 13 | - | nF | |
| C_{oss} | output capacitance | | | - | 575 | - | pF | |
| C_{rss} | reverse transfer capacitance | | | - | 60 | - | pF | |
| E_{oss} | Coss stored energy | | | - | 290 | - | μJ | |
| $t_{d(on)}$ | turn-on delay time | | $V_{DS} = 800 V$; $V_{GS} = -4 V/18 V$; $R_{G(off)} = 2.4 \Omega$; $R_{G(on)} = 2.4 \Omega$; $I_D = 150 A$; $L = 100 \mu H$; $T_j = 25 \text{ }^\circ C$ | | - | 82 | - | ns |
| t_r | rise time | | | | - | 70 | - | ns |
| $t_{d(off)}$ | turn-off delay time | | | | - | 210 | - | ns |
| t_f | fall time | | | - | 75 | - | ns | |
| E_{on} | turn-on energy | | | - | 5.4 | - | mJ | |
| E_{off} | turn-off energy | | | - | 2.3 | - | mJ | |

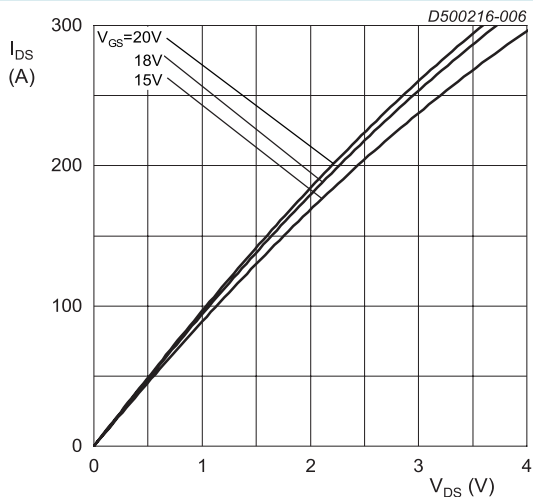
| Body diode | | | | | | | |
|--------------------------------|-------------------------------|--|-------|-----|--------|-----|------|
| Symbol | Parameter | Conditions | Notes | Min | Typ | Max | Unit |
| Static characteristics | | | | | | | |
| V _{SD} | source-drain voltage | V _{GS} = -4 V; I _{SD} = 150 A; T _j = 25 °C | | - | 5.8 | - | V |
| | | V _{GS} = -4 V; I _{SD} = 150 A; T _j = 150 °C | | - | 5.2 | - | V |
| Dynamic characteristics | | | | | | | |
| I _{rrm} | reverse recovery current | I _{SD} = 150 A; V _{GS} = -4 V/18 V; V _R = 600 V; di/dt = 2700 A/μs; R _{G(ext)} = 5.1 Ω; T _j = 25 °C | | - | 62 | - | A |
| t _{rr} | reverse recovery time | | | - | 27 | - | ns |
| Q _r | recovered charge | | | - | 928 | - | nC |
| E _{rec} | reverse recovery energy | | | - | 61 | - | μJ |
| NTC thermistor | | | | | | | |
| Symbol | Parameter | Conditions | Notes | Min | Typ | Max | Unit |
| R ₂₅ | Rated resistance | T _{NTC} = 25 °C | | - | 5000 | - | Ω |
| R ₁₀₀ | | T _{NTC} = 100 °C | | | 493±5% | | Ω |
| B _{25/50} | B-value | $R_2 = R_{25} \exp[B_{25/50}(1/T_2 - 1/(298.15K))]$ | | | 3380 | | K |
| | Maximum operating temperature | | | - | 200 | - | °C |
| | Dissipation costant | | | - | 2 | - | mW/K |
| | Thermal time constant | | | - | ≤10 | - | s |



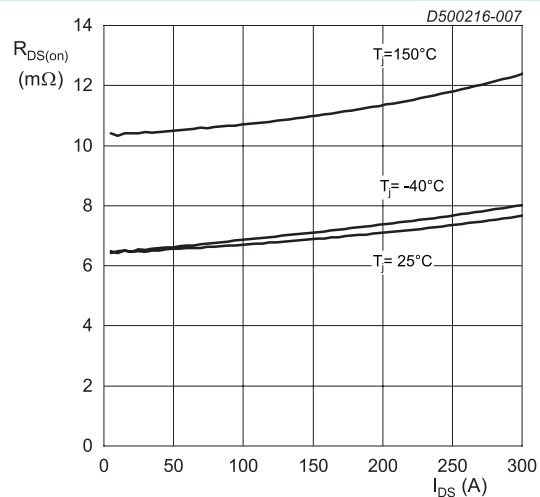
$T_j = -40\text{ }^\circ\text{C}; t_p < 200\text{ }\mu\text{s}$
Fig. 4. Output characteristics; drain current as a function of drain-source voltage; typical values



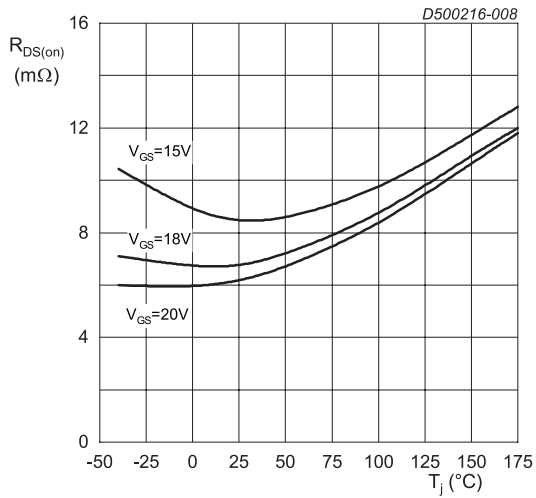
$T_j = 25\text{ }^\circ\text{C}; t_p < 200\text{ }\mu\text{s}$
Fig. 5. Output characteristics; drain current as a function of drain-source voltage; typical values



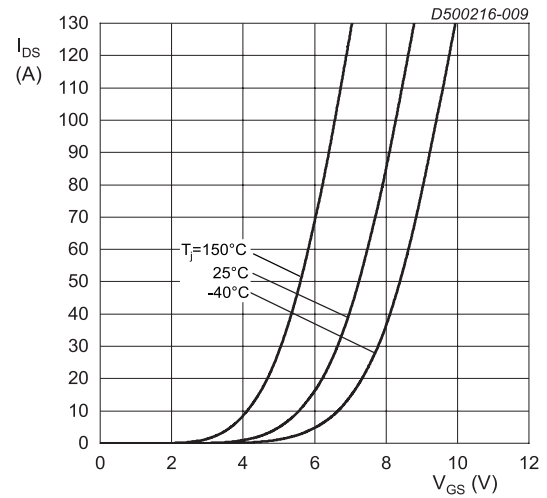
$T_j = 150\text{ }^\circ\text{C}; t_p < 200\text{ }\mu\text{s}$
Fig. 6. Output characteristics; drain current as a function of drain-source voltage; typical values



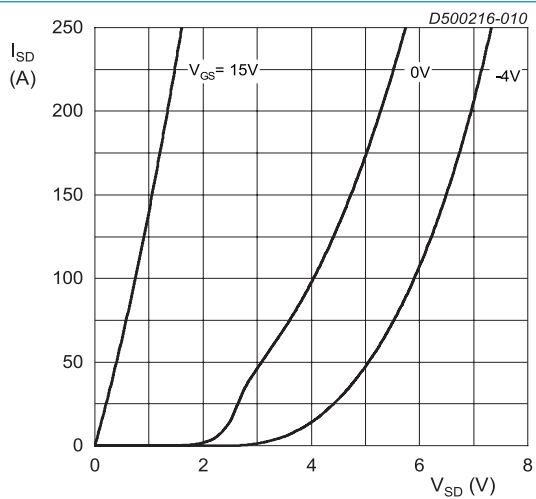
$V_{GS} = 18\text{ V}; t_p < 200\text{ }\mu\text{s}$
Fig. 7. Drain-source on-state resistance as a function of drain current; typical values



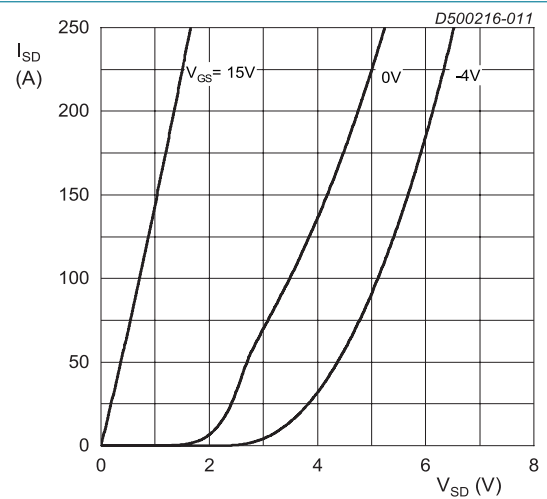
$I_{DS} = 150 A; t_p < 200 \mu s$
Fig. 8. Drain-source on-state resistance as a function of junction temperature



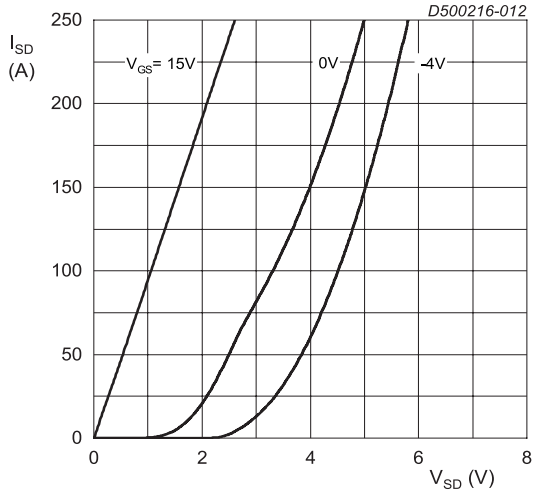
$V_{DS} = 20 V; t_p < 200 \mu s$
Fig. 9. Transfer characteristics; drain current as a function of gate-source voltage; typical values



$T_j = -40^{\circ}C; t_p < 200 \mu s$
Fig. 10. Body diode forward characteristics; typical values

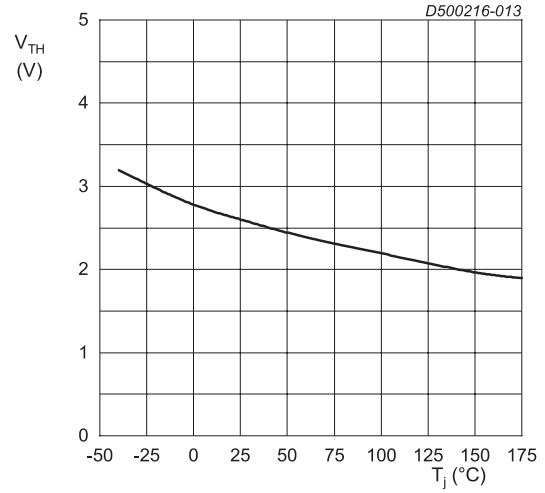


$T_j = 25^{\circ}C; t_p < 200 \mu s$
Fig. 11. Body diode forward characteristics; typical values



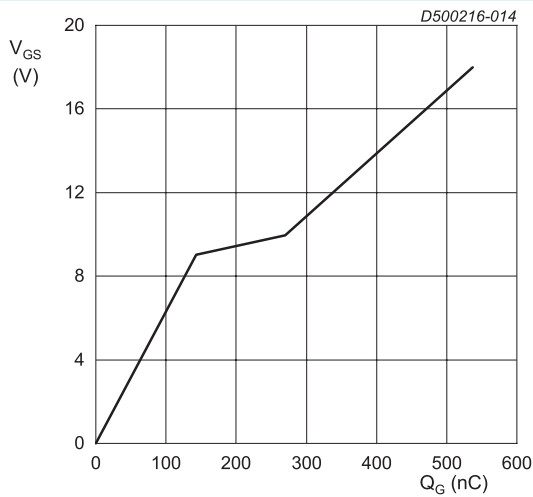
$T_j = 150\text{ }^\circ\text{C}$; $t_p < 200\text{ }\mu\text{s}$

Fig. 12. Body diode forward characteristics; typical values



$V_{DS} = 10\text{ V}$; $I_{DS} = 48\text{ mA}$

Fig. 13. Threshold voltage as a function of junction temperature



$I_{DS} = 150\text{ A}$; $I_{GS} = 0.1\text{ mA}$; $V_{DS} = 800\text{ V}$; $T_j = 25\text{ }^\circ\text{C}$

Fig. 14. Gate-source voltage as a function of gate charge; typical values

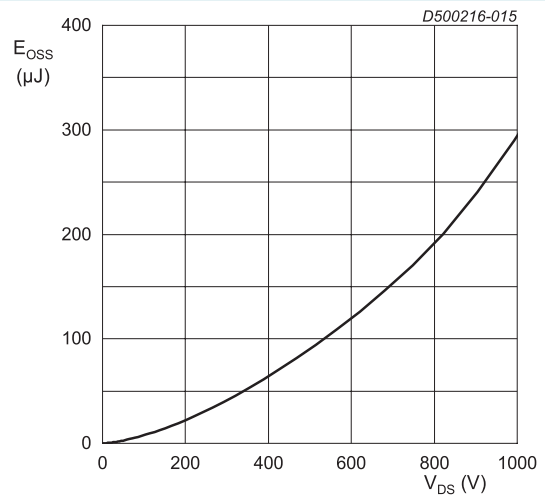
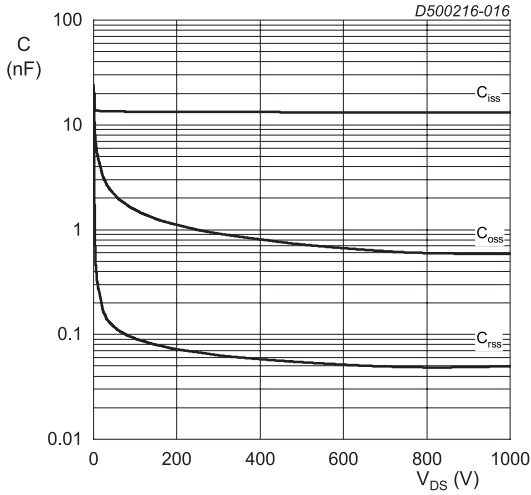
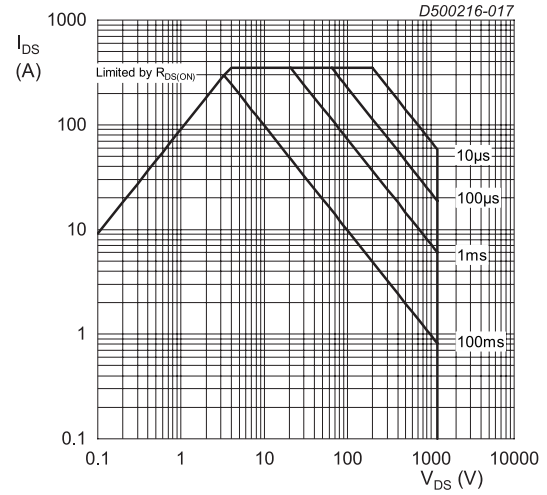


Fig. 15. Output capacitor stored energy as a function of drain-source voltage



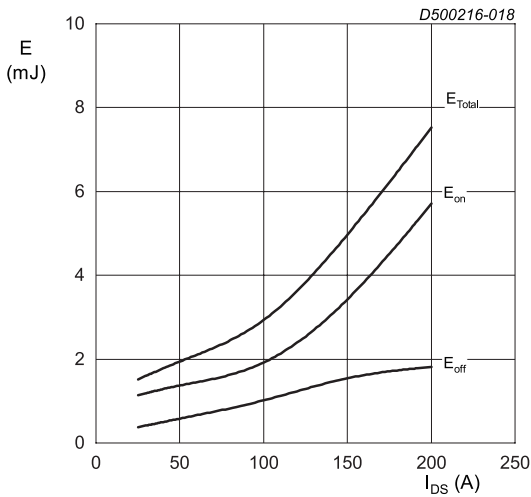
$V_{DS} = 0 - 1000 \text{ V}$
 $T_j = 25 \text{ }^\circ\text{C}; V_{AC} = 25 \text{ mV}; f = 1 \text{ MHz}$

Fig. 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



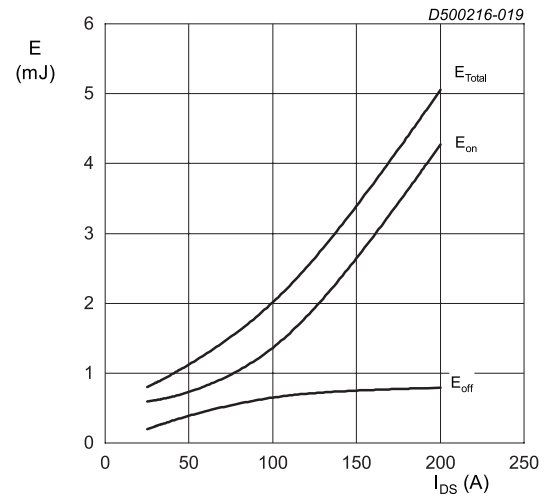
$T_j = 25 \text{ }^\circ\text{C}; D = 0$
 Parameter: t_p

Fig. 17. Forward bias safe operating area



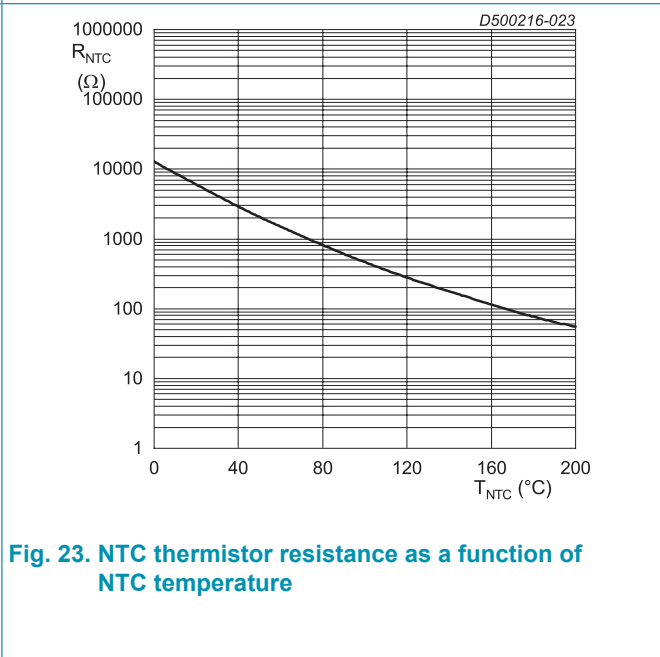
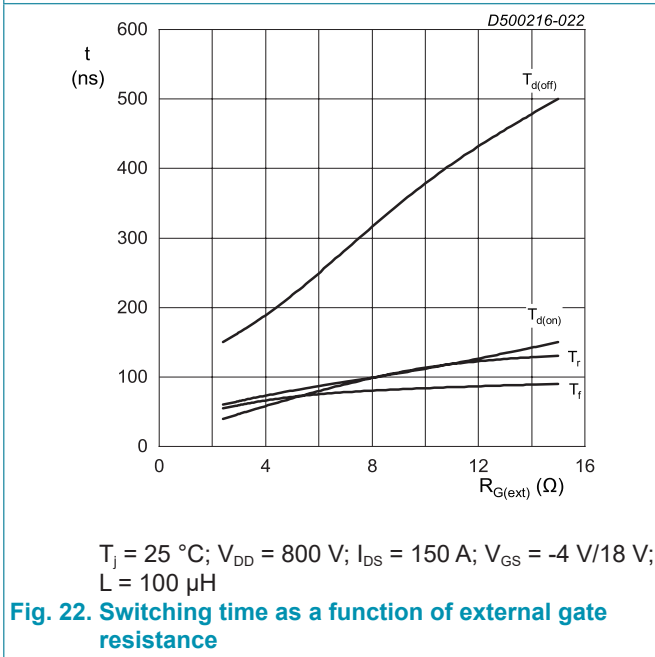
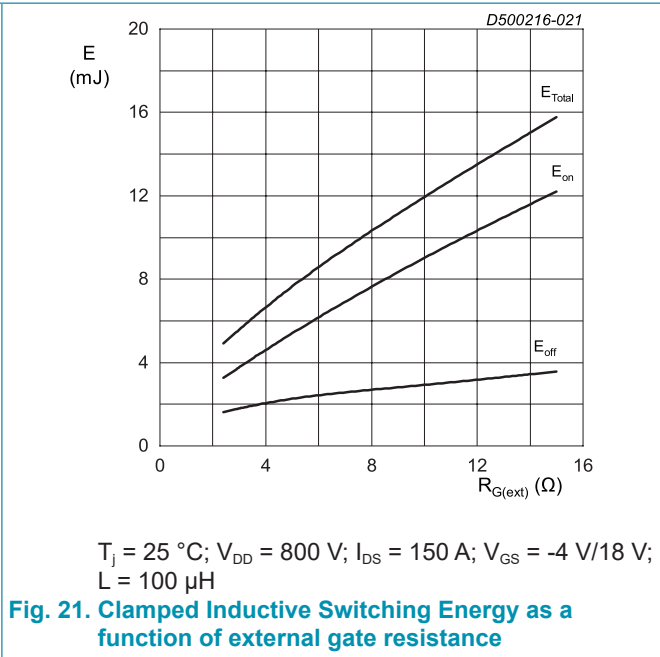
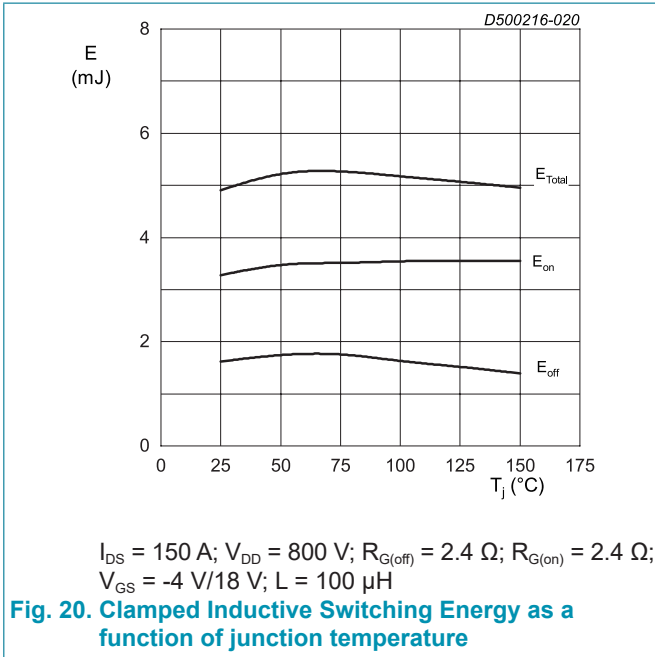
$T_j = 25 \text{ }^\circ\text{C}; V_{DD} = 800 \text{ V}; R_{G(off)} = 2.4 \text{ } \Omega; R_{G(on)} = 2.4 \text{ } \Omega;$
 $V_{GS} = -4 \text{ V}/18 \text{ V}; L = 100 \text{ } \mu\text{H}$

Fig. 18. Clamped Inductive Switching Energy as a function of drain current



$T_j = 25 \text{ }^\circ\text{C}; V_{DD} = 600 \text{ V}; R_{G(off)} = 2.4 \text{ } \Omega; R_{G(on)} = 2.4 \text{ } \Omega;$
 $V_{GS} = -4 \text{ V}/18 \text{ V}; L = 100 \text{ } \mu\text{H}$

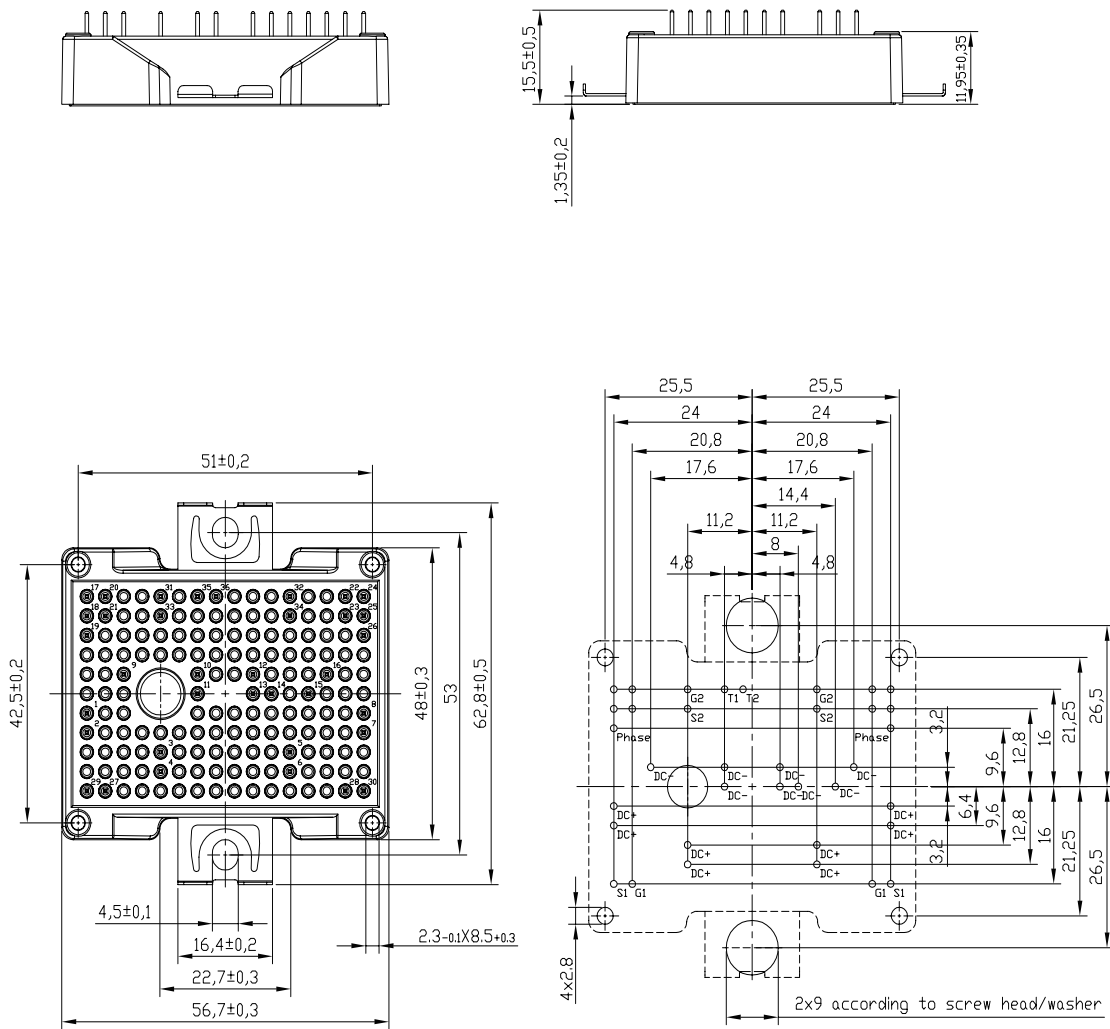
Fig. 19. Clamped Inductive Switching Energy as a function of drain current



11. Package outline

Package Outline

Dimensions in mm



12. Legal information

Data sheet status

| Document status [1][2] | Product status [3] | Definition |
|--------------------------------|--------------------|---|
| Objective [short] data sheet | Development | This document contains data from the objective specification for product development. |
| Preliminary [short] data sheet | Qualification | This document contains data from the preliminary specification. |
| Product [short] data sheet | Production | This document contains the product specification. |

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <http://www.ween-semi.com>.

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